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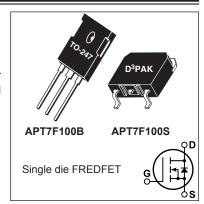


APT7F100B APT7F100S

1000V, 7A, 2.0Ω Max

N-Channel FREDFET

POWER MOS 8® is a high speed, high voltage N-channel switch-mode power MOSFET. This 'FREDFET' version has a drain-source (body) diode that has been optimized for high reliability in ZVS phase shifted bridge and other circuits through reduced t_{rr} , soft recovery, and high recovery dv/dt capability. Low gate charge, high gain, and a greatly reduced ratio of C_{rss}/C_{iss} result in excellent noise immunity and low switching loss. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control di/dt during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency.



FEATURES

- · Fast switching with low EMI
- · Low trr for high reliability
- · Ultra low Crss for improved noise immunity
- · Low gate charge
- · Avalanche energy rated
- RoHS compliant

TYPICAL APPLICATIONS

- · ZVS phase shifted and other full bridge
- · Half bridge
- · PFC and other boost converter
- Buck converter
- · Single and two switch forward
- Flyback

Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
	Continuous Drain Current @ T _C = 25°C	7	
'D	Continuous Drain Current @ T _C = 100°C	5	Α
I _{DM}	Pulsed Drain Current ^①	27	
V _{GS}	Gate-Source Voltage	±30	V
E _{AS}	Single Pulse Avalanche Energy [©]	415	mJ
I _{AR}	Avalanche Current, Repetitive or Non-Repetitive	4	Α

Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Тур	Max	Unit	
P _D	Total Power Dissipation @ T _C = 25°C			290	W	
$R_{\theta JC}$	Junction to Case Thermal Resistance			0.43	°C/W	
$R_{\theta CS}$	Case to Sink Thermal Resistance, Flat, Greased Surface		0.15		C/VV	
T_J , T_{STG}	Operating and Storage Junction Temperature Range	-55		150	°C	
T _L	Soldering Temperature for 10 Seconds (1.6mm from case)			300		
W _T	Package Weight		0.22		OZ	
			6.2		g	
Torque	Mounting Torque (TO-247 Package), 6-32 or M3 screw			10	in·lbf	
				1.1	N·m	

- J							
Symbol	Parameter	Test Conditions		Min	Тур	Max	Unit
V _{BR(DSS)}	Drain-Source Breakdown Voltage	V _{GS} = 0V, I _D = 250μA		1000			V
$\Delta V_{BR(DSS)}/\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	Reference to 25°C, I _D = 250μA			1.15		V/°C
R _{DS(on)}	Drain-Source On Resistance [®]	$V_{GS} = 10V, I_{D} = 4A$			1.76	2.0	Ω
V _{GS(th)}	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 0.5 \text{mA}$		2.5	4	5	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Threshold Voltage Temperature Coefficient				-10		mV/°C
	Zara Cata Valtara Dunin Current	V _{DS} = 1000V	T _J = 25°C			250	
DSS	Zero Gate Voltage Drain Current	V _{GS} = 0V	T _J = 125°C			1000	μA
I _{GSS}	Gate-Source Leakage Current	V _{GS} = ±30V				±100	nA

Dvnamic Characteristics

T₁ = 25°C unless otherwise specified

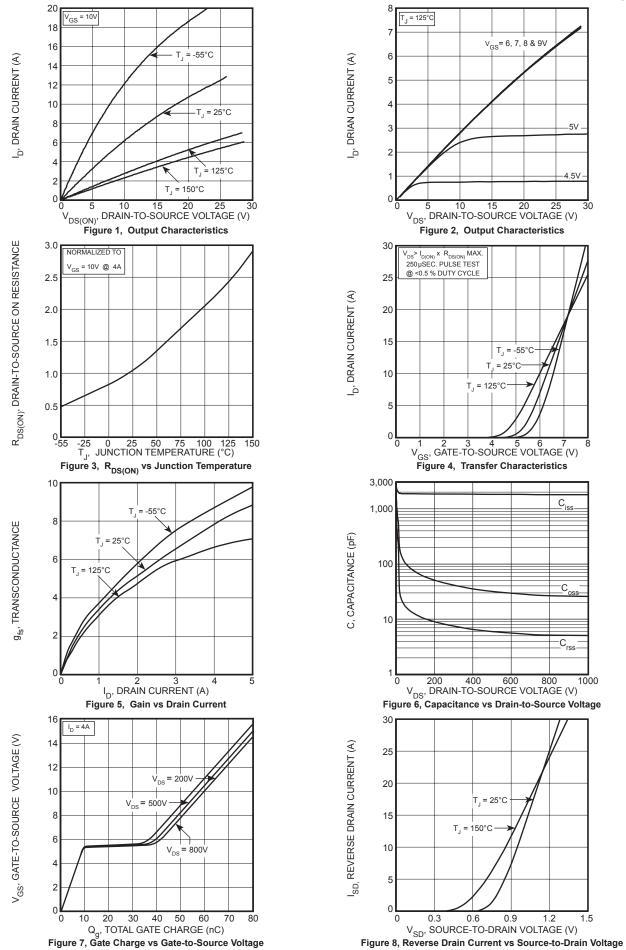
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
9 _{fs}	Forward Transconductance	V _{DS} = 50V, I _D = 4A		7.5		S
C _{iss}	Input Capacitance	V 0V V 0FV		1800		
C _{rss}	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{DS} = 25V$ f = 1MHz		25		
C _{oss}	Output Capacitance	1 111112		158		
$C_{o(cr)} @$	Effective Output Capacitance, Charge Related	V = 0V V = 0V45 C70V		65		pF
C _{o(er)} ⑤	Effective Output Capacitance, Energy Related	V _{GS} = 0V, V _{DS} = 0V to 670V		33		
Q _g	Total Gate Charge	V 04:40V 1 4A		58		
Q_{gs}	Gate-Source Charge	$V_{GS} = 0 \text{ to } 10V, I_{D} = 4A,$		10		nC
Q_{gd}	Gate-Drain Charge	V _{DS} = 500V		27		
t _{d(on)}	Turn-On Delay Time	Resistive Switching		24		
t _r	Current Rise Time	V _{DD} = 670V, I _D = 4A		26		ns
t _{d(off)}	Turn-Off Delay Time	$R_{G} = 10\Omega^{\odot}, V_{GG} = 15V$		77		115
t _f	Current Fall Time			22		

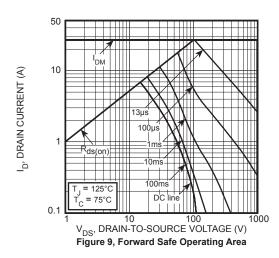
Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
I _s	Continuous Source Current (Body Diode)	MOSFET symbol showing the integral reverse p-n			7	А
I _{SM}	Pulsed Source Current (Body Diode) ^①	junction diode (body diode)	5		27	^
V _{SD}	Diode Forward Voltage	$I_{SD} = 4A, T_{J} = 25^{\circ}C, V_{GS} = 0V$			1.2	V
t _{rr}	Reverse Recovery Time Reverse Recovery Charge	T _J = 25°C		133	152	ns
Trr		T _J = 125°C		209	251	113
Q _{rr}		$I_{SD} = 4A^{\textcircled{3}}$ $T_{J} = 25^{\circ}C$.56		μC
		$di_{SD}/dt = 100A/\mu s$ $T_J = 125^{\circ}C$		1.2		μΟ
	Reverse Recovery Current	$V_{DD} = 100V$ $T_{J} = 25^{\circ}C$		7		Α
'rrm		T _J = 125°C		9		
dv/dt	Peak Recovery dv/dt	$I_{SD} \le 4A$, di/dt $\le 1000A/\mu s$, $V_{DD} = 500V$, $T_J = 125^{\circ}C$			25	V/ns

- 1 Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
- ② Starting at $T_J = 25$ °C, L = 53mH, $R_G = 25\Omega$, $I_{AS} = 4A$.
- (3) Pulse test: Pulse Width < 380µs, duty cycle < 2%.
- C_{o(cr)} is defined as a fixed capacitance with the same stored charge as C_{OSS} with V_{DS} = 67% of V_{(BR)DSS}.
 C_{o(er)} is defined as a fixed capacitance with the same stored energy as C_{OSS} with V_{DS} = 67% of V_{(BR)DSS}. To calculate C_{o(er)} for any value of V_{DS} less than V_{(BR)DSS}, use this equation: C_{o(er)} = -3.43E-8/V_{DS}^2 + 1.44E-8/V_{DS} + 5.38E-11.
- 6 R_G is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)

Microsemi reserves the right to change, without notice, the specifications and information contained herein.





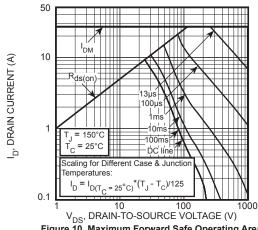


Figure 10, Maximum Forward Safe Operating Area

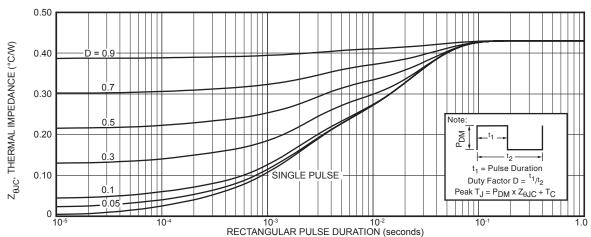


Figure 11. Maximum Effective Transient Thermal Impedance Junction-to-Case vs Pulse Duration

TO-247 (B) Package Outline

D³PAK Package Outline

